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Date: December 5, 2005 File Number: 5308.127DV
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Re: Patent Application No. 10706641
Inventor: S. T. Allen et al.
Patent Application Entitled *Methods of Fabricating Silicon Carbide Metal-Semiconductor Field Effect Transistors*

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Attorney's Docket No. 5308-127DV

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re: Allen et al.

Confirmation No.: 7025

Application No.: 10/706,641

Group Art Unit: 2826

Filed: November 12, 2003

Examiner: Ahmed N. Sefer

For: **METHODS OF FABRICATING SILICON CARBIDE METAL-
SEMICONDUCTOR FIELD EFFECT TRANSISTORS**

Date: December 5, 2005

Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

AMENDMENT RESPONSIVE EX PARTE QUAYLE ACTION

Sir:

Applicants provide the present Amendment to address the issue raised in the Office Action mailed October 6, 2005.

Amendments to the Claims are reflected in the listing of claims, which begins on page 2 of this paper.

Remarks/Arguments begin on page 13 of this paper.